

**Notice of References Cited**

Application/Control No.

09/784,340

Applicant(s)/Patent Under  
Reexamination  
WEI ET AL.

Examiner

Delia M. Ramirez

Art Unit

1652

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0029221	02-2004	Baker et al.	435/69.1
*	B	US-2004/0029125	02-2004	Policky et al.	435/6
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/79468 A2	10-2001	WIPO	Policky et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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	X	

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